

May 1988 Revised August 1999

74F379

Quad Parallel Register with Enable

General Description

The 74F379 is a 4-bit register with buffered common Enable. This device is similar to the 74F175 but features the common Enable rather than common Master Reset.

Features

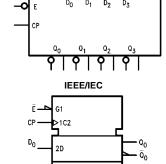
- Edge triggered D-type inputs
- Buffered positive edge-triggered clock
- Buffered common enable input
- True and complement outputs

Ordering Code:

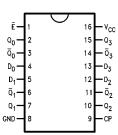
	Order Number	Package Number	Package Description						
	74F379SC	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow						
74F379SJ M16D		M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide						
	74F379PC N16E		16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide						

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Din Name	Paraminetian.	U.L.	Input I _{IH} /I _{IL}
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}
Ē	Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA
D ₀ –D ₃	Data Inputs	1.0/1.0	20 μA/–0.6 mA
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μA/-0.6 mA
$Q_0 - Q_3$	Flip-Flop Outputs	50/33.3	−1 mA/20 mA
$\overline{Q}_0 - \overline{Q}_3$	Complement Outputs	50/33.3	−1 mA/20 mA

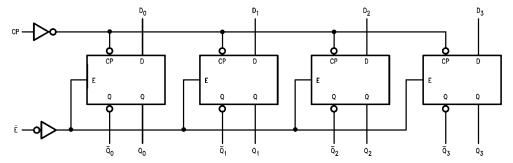
Functional Description

The 74F379 consists of four edge-triggered D-type flipflops with individual D inputs and Q and \overline{Q} outputs. The Clock (CP) and Enable (\overline{E}) inputs are common to all flipflops. When the \overline{E} is input HIGH, the register will retain the present data independent of the CP input. The D_n and \overline{E} inputs can change when the clock is in either state, provided that the recommended setup and hold times are observed.

Truth Table

	Inputs	Outputs			
Ē	E CP		Q _n	\overline{Q}_n	
Н		Χ	NC	NC	
L	~	Н	Н	L	
L	~	L	L	Н	

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

-65°C to +150°C

Input Current (Note 2)

-30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{ll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{3-STATE Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$

Current Applied to Output

Storage Temperature

Recommended Operating Conditions

Free Air Ambient Temperature 0° C to $+70^{\circ}$ C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

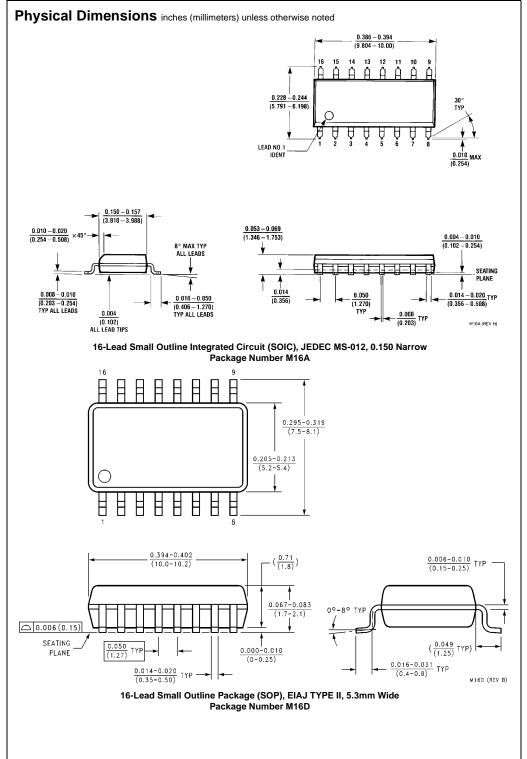
Symbol	Parameter		Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.5			V	Min	I _{OH} = -1 mA
	Voltage	5% V _{CC}	2.7			V	IVIII	$I_{OH} = -1 \text{ mA}$
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	I _{OL} = 20 mA
	Voltage							
I _{IH}	Input HIGH				5.0	^	Mau	\/ 0.7\/
	Current				5.0	μА	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current				7.0	^	Max	V 70V
	Breakdown Test				7.0	μА	IVIAX	V _{IN} = 7.0V
I _{CEX}	Output HIGH				50	^	Max	V V
	Leakage Current				50	μА	IVIAX	$V_{OUT} = V_{CC}$
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
	Test		4.75			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				2.75	^	0.0	V _{IOD} = 150 mV
	Circuit Current				3.75	μА	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V
Ios	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V
I _{CCL}	Power Supply Current			28	40	mA	Max	V _O = LOW

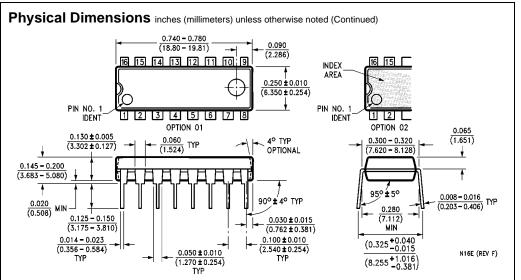
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	100	140		75		100		MHz
t _{PLH}	Propagation Delay	3.5	5.0	6.5	3.0	8.5	3.5	7.5	20
t _{PHL}	CP to Q_n , \overline{Q}_n	5.0	6.5	8.5	4.0	10.0	5.0	9.5	ns

AC Operating Requirements

		T _A =	$T_A = +25^{\circ}C$		$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$		$T_A = 0$ °C to +70°C	
Symbol	Parameter	$V_{CC} = +5.0V$		$V_{CC} = +5.0V$		$\textbf{V}_{\textbf{CC}} = +5.0\textbf{V}$		Units
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	3.0		4.0			3.0	
t _S (L)	D _n to CP	3.0		4.0			3.0	ns
t _H (H)	Hold Time, HIGH or LOW	1.0		2.0			1.0	115
t _H (L)	D _n to CP	1.0		2.0			1.0	
t _S (H)	Setup Time, HIGH or LOW	6.0		8.0			6.0	
t _S (L)	E to CP	6.0		8.0			6.0	ns
t _H (H)	Hold Time, HIGH or LOW	0		0			0	115
t _H (L)	E to CP	0		0			0	
t _W (H)	CP Pulse Width	4.0		5.0			4.0	ns
t _W (L)	HIGH or LOW	5.0		7.0			5.0	115





16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N16E

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